2SB1073G

Silicon PNP epitaxial planar type

For low-frequency amplification

■ Features

- Low collector-emitter saturation voltage V_{CE(sat)}
- Large peak collector current I_{CP}
- Mini Power type package, allowing downsizing of the equipment and automatic insertion through the tape packing and the magazine packing.

■ Absolute Maximum Ratings $T_a = 25^{\circ}C$

Parameter	Symbol	Rating	Unit	
Collector-base voltage (Emitter open)	V_{CBO}	-30	V	
Collector-emitter voltage (Base open)	V_{CEO}	-20	V	
Emitter-base voltage (Collector open)	V _{EBO}	-7	V	
Collector current	I_{C}	-4	A	
Peak collector current	I_{CP}	-7	A	
Collector power dissipation *	P _C	1	W	
Junction temperature	T _j	150	°C	
Storage temperature	T _{stg}	-55 to +150	°C	

Note) *: Print circuit board: Copper foil area of 1 cm² or more, and the board thickness of 1.7 mm for the collector portion

Package

- Code MiniP3-F2
- Pin Name
 - 1: Base
 - 2: Collector
 - 3: Emitter
- Marking Symbol: I

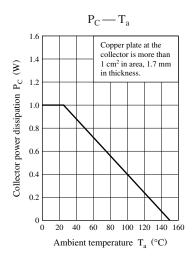
■ Electrical Characteristics $T_a = 25$ °C ± 3 °C

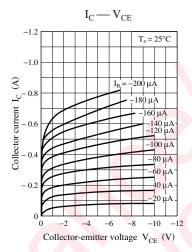
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-base voltage (Emiter open)	V_{CBO}	$I_C = -10 \mu\text{A}, I_E = 0$	-30			V
Collector-emitter voltage (Base open)	V _{CEO}	$I_C = -1 \text{ mA}, I_B = 0$	-20			V
Emiter-base voltage (Collector open)	V_{EBO}	$I_E = -10 \mu\text{A}, I_C = 0$	-7			V
Collector-base cutoff current (Emitter open)	I_{CBO}	$V_{CB} = -30 \text{ V}, I_E = 0$			- 0.1	μΑ
Emitter-base cutoff current (Collector open)	I_{EBO}	$V_{EB} = -7 \text{ V}, I_C = 0$			- 0.1	μΑ
Forward current transfer ratio *1, 2	h _{FE}	$V_{CE} = -2 \text{ V}, I_{C} = -2 \text{ A}$	120		315	_
Collector-emitter saturation voltage *1	V _{CE(sat)}	$I_C = -3 \text{ A}, I_B = -0.1 \text{ A}$		- 0.6	-1.0	V
Transition frequency	f_T	$V_{CB} = -6 \text{ V}, I_E = 50 \text{ mA}, f = 200 \text{ MHz}$		120		MHz
Collector output capacitance	C _{ob}	$V_{CB} = -20 \text{ V}, I_E = 0, f = 1 \text{ MHz}$		40		pF
(Common base, input open circuited)						

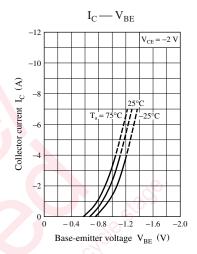
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

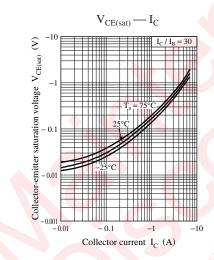
- 2. *1: Pulse measurement
 - *2: Rank classification

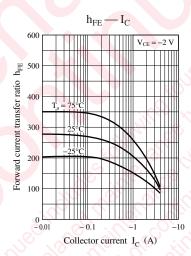
Rank	Q	R
h_{FE}	120 to 205	180 to 315

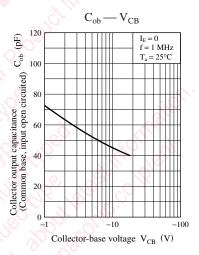






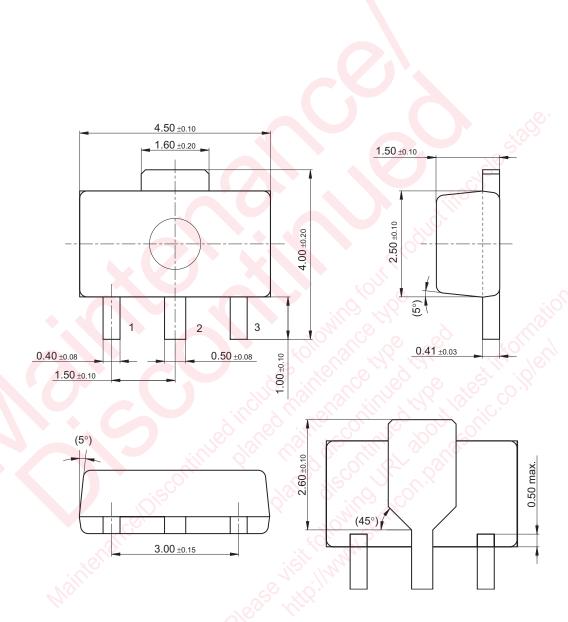






2 SJD00332AED

MiniP3-F2 Unit: mm



SJD00332AED 3

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